Product data sheet

1. General description

Silicon Carbide MOSFET in a TSPAK plastic package with top side cooling structure, designed for high frequency, high efficiency systems.



2. Features and benefits

- Automotive Qualified (AEC-Q101)
- · Reduced cooling requirements
- Low on-resistance
- Fast switching speed
- · 0V turn-off gate voltage for simple gate driver
- 100% UIS Tested
- Easy to parallel
- Controllable dV/dt for optimized EMI
- RoHS compliant



3. Applications

- Automotive on board chargers
- Automotive DC-DC converters
- · Automotive electric compressor motor drives
- HV battery management systems

4. Quick reference data

Table 1. Quick reference data

Symbol	Parameter	Conditions	Notes	Values		Unit	
Absolute	maximum rating						
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C			1200		V
I _D	drain current	V _{GS} = 18 V; T _{mb} = 25 °C			96.8		Α
P _{tot}	total power dissipation	T _{mb} = 25 °C, T _j = 175 °C			540		W
Tj	junction temperature			-55 to 175		°C	
Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
$R_{\mathrm{DS(on)}}$	drain-source on-state resistance	$V_{GS} = 15 \text{ V}; I_D = 40 \text{ A}; T_j = 25 ^{\circ}\text{C}$		-	30	-	mΩ
		V_{GS} = 18 V; I_D = 40 A; T_j = 25 °C		-	24	40	mΩ
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 40 \text{ A}$; $V_{DS} = 800 \text{ V}$; $V_{GS} = -4 \text{ V}/18 \text{ V}$;		-	151	-	nC
Q_{GD}	gate-drain charge	T _j = 25 °C		-	21	-	nC
Source-di	rain diode		,			,	
Q _r	recovered charge	I_{SD} = 40 A; di/dt = 500 A/µs; V_{DS} = 400 V; T_j = 25 °C		-	129	-	nC

5. Pinning information

Table 2. Pinning information

Pin	Symbol	Description	Simplified outline	Graphic symbol
1	G	gate	89	D
2	SS	source sense		
3-7	S	source	МВ	$G \longrightarrow A$
8-9 mb	D	mounting base; connected to drain	7 6 5 4 3 2 1	SS Sym301 S

6. Ordering information

Table 3. Ordering information

Type number	Package Name	Orderable part number	Packing method	Small packing quantity		Package issue date
WNSC2M30120TB-A	TSPAK	WNSC2M30120TB-A6J	Reel	600	TSPAKH	06-Dec-2024

7. Marking

Table 4. Marking codes

Type number	Marking codes
WNSC2M30120TB-A	WNSC2M 30120TB-A

8. Limiting values

Table 5. Limiting values

In accordance with the Absolute Maximum Rating System (IEC 60134).

Symbol	Parameter	Conditions	Notes	Values	Unit
V _{DS}	drain-source voltage	25 °C ≤ T _j ≤ 175 °C		1200	V
$V_{\rm GS,max}$	gate-source voltage	Absolute maximum values		-10 to 22	V
$V_{GS,op}$	gate-source voltage	Recommended operational values		-4 to 18	V
P _{tot}	total power dissipation	T _{mb} = 25 °C, T _j = 175 °C		540	W
I _D	drain current	V _{GS} = 18 V; T _{mb} = 25 °C		96.8	Α
		V _{GS} = 18 V; T _{mb} = 100 °C		68.4	Α
I _{DM}	peak drain current	pulse width t _p limited by T _{jmax}	Fig.17	190	Α
Is	continuous diode current	V _{GS} = -4 V; T _{mb} = 25 °C		73.1	А
I _{SM}	pulse diode current	V_{GS} = -4 V; pulse width t_p limited by T_{jmax}		190	А
E _{as}	single pulse drain-to- source avalanche	I_{AS} = 20 A; L = 1 mH; V_{DD} = 100 V; T_j = 25 °C		200	mJ
T _{stg}	storage temperature			-55 to 175	°C
T _j	junction temperature			-55 to 175	°C
$T_{sld(M)}$	peak soldering temperature			260	°C

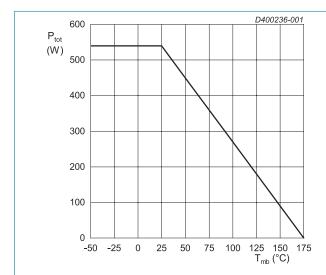


Fig. 1. Total power dissipation as a function of mounting base temperature; maximum values

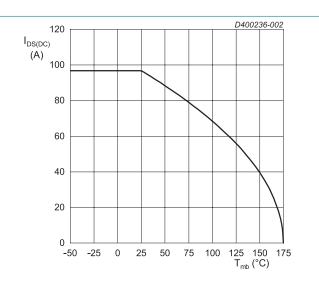


Fig. 2. Continuous Drain Current as a function of mounting base temperature

9. Thermal & Mechanical characteristics

Table 6. Thermal & Mechanical characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
R _{th(j-mb)}	thermal resistance from junction to mounting base			-	0.28	-	K/W
$R_{\text{th(j-a)}}$	thermal resistance from junction to ambient	in free air		-	40	-	K/W

Note: Device is ESD sensitive. Handling precautions are recommended.

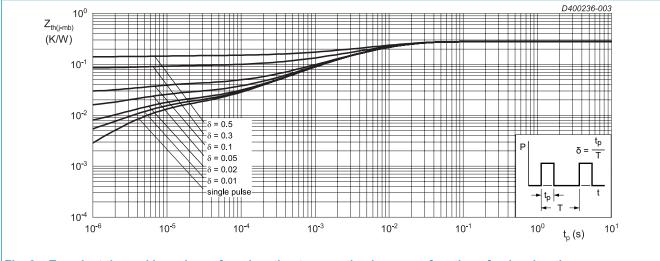


Fig. 3. Transient thermal impedance from junction to mounting base as a function of pulse duration

10. Characteristics

Table 7. Characteristics

Symbol	Parameter	Conditions	Notes	Min	Тур	Max	Unit
Static cha	racteristics						
$V_{(BR)DSS}$	drain-source breakdown voltage	$I_D = 100 \mu A; V_{GS} = 0 V; T_j = 25 ^{\circ}C$		1200	-	-	V
	gate-source threshold	$I_D = 12 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 25 \text{ °C}$		1.9	2.6	3.5	V
	voltage	$I_D = 12 \text{ mA}; V_{DS} = 10 \text{ V}; T_j = 175 ^{\circ}\text{C}$		-	1.9	-	V
I _{DSS}	drain leakage current	$V_{DS} = 1200 \text{ V}; V_{GS} = 0 \text{ V}; T_j = 25 \text{ °C}$		-	0.2	100	μA
		V _{DS} = 1200 V; V _{GS} = 0 V; T _j = 175 °C		-	2	-	μA
I _{GSS}	gate leakage current	V _{GS} = 22 V; V _{DS} = 0 V; T _j = 25 °C		-	10	100	nA
		$V_{GS} = -10 \text{ V}; V_{DS} = 0 \text{ V}; T_j = 25 \text{ °C}$		-	10	100	nA
R _{DS(on)}	drain-source on-state	V _{GS} = 15 V; I _D = 40 A; T _j = 25 °C		-	30	-	mΩ
	resistance	V _{GS} = 18 V; I _D = 40 A; T _j = 25 °C		-	24	40	mΩ
		V _{GS} = 18 V; I _D = 40 A; T _j = 175 °C		-	48	-	mΩ
$R_{\scriptscriptstyle G}$	gate resistance	f = 1 MHz; T _j = 25 °C		-	0.8	-	Ω
g _{fs}	transconductance	$V_{DS} = 20 \text{ V}; I_D = 40 \text{ A}; T_j = 25 \text{ °C}$		-	27	-	S
Dynamic	characteristics						
Q _{G(tot)}	total gate charge	$I_D = 40 \text{ A}; V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V};$		-	151	-	nC
Q _{GS}	gate-source charge	T _j = 25 °C		-	63	-	nC
Q_{GD}	gate-drain charge			-	21	-	nC
C _{iss}	input capacitance	V _{DS} = 1000 V; V _{GS} = 0 V; f = 1 MHz;		-	3305	-	pF
C _{oss}	output capacitance	T _j = 25 °C		-	139	-	pF
C _{rss}	reverse transfer capacitance			-	12	-	pF
E _{oss}	Coss stored energy			-	69.5	-	μJ
t _{d(on)}	turn-on delay time	$V_{DS} = 800 \text{ V}; V_{GS} = -4 \text{ V}/18 \text{ V}; R_{G(ext)} = 5.1$		-	27	-	ns
t _r	rise time	$Ω$; $I_D = 40 A$; $L = 100 \mu H$; $T_j = 25 °C$		-	34	-	ns
$t_{d(off)}$	turn-off delay time			-	51	-	ns
t _f	fall time			-	14	-	ns
E _{on}	turn-on energy (Sic Diode FWD)		Fig.20	-	552	-	μJ
E _{off}	turn-off energy (Sic Diode FWD)		Fig.20	-	162	-	μJ
E _{on}	turn-on energy (Body Diode FWD)		Fig.20	-	671	-	μJ
E _{off}	turn-off energy (Body Diode FWD)		Fig.20	-	154	-	μJ
Source-di	rain diode				1	1	1
V _{SD}	source-drain voltage	V _{GS} = 0 V; I _{SD} = 20 A; T _j = 25 °C		-	3.2	-	V
		V _{GS} = -4 V; I _{SD} = 20 A; T _j = 25 °C		-	4.8	-	V
		V _{GS} = -4 V; I _{SD} = 20 A; T _j = 175 °C		-	4.2	-	V
t _{rr}	reverse recovery time	$I_{SD} = 40 \text{ A}$; di/dt = 500 A/ μ s; $V_{DS} = 400 \text{ V}$;		-	33.4	-	ns
Q _r	recovered charge	T _j = 25 °C		-	129	-	nC
I _{rrm}	reverse recovery current			_	6.9	-	Α

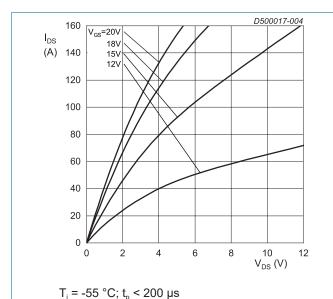


Fig. 4. Output characteristics; drain current as a function of drain-source voltage; typical values

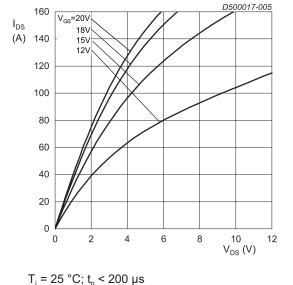
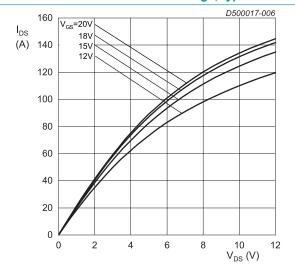
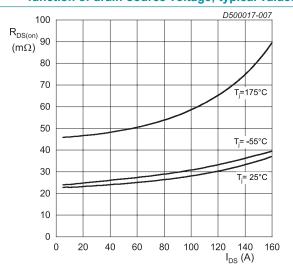


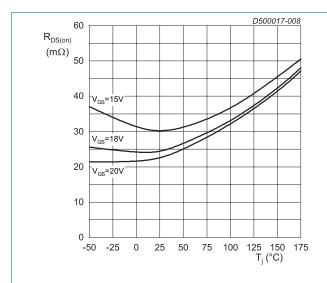
Fig. 5. Output characteristics; drain current as a function of drain-source voltage; typical values



T_j = 175 °C; t_p < 200 μs Fig. 6. Output characteristics; drain current as a function of drain-source voltage; typical values

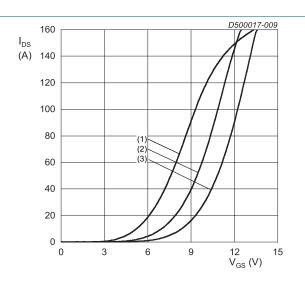


 V_{GS} = 18 V; t_p < 200 µs Fig. 7. Drain-source on-state resistance as a function of drain current; typical values



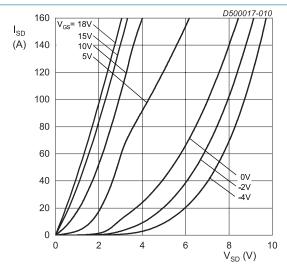
 I_{DS} = 40 A; t_p < 200 μs

Fig. 8. Drain-source on-state resistance as a function of junction temperature

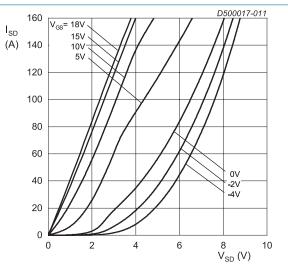


 V_{DS} = 20 V; t_p < 200 μ s

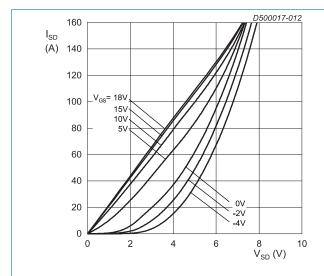
Fig. 9. Transfer characteristics; drain current as a function of gate-source voltage; typical values



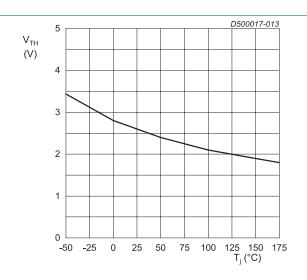
T_j = -55 °C; t_p < 200 μs Fig. 10. Body diode forward characteristics; typical values



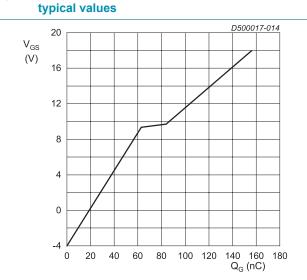
T_j = 25 °C; t_p < 200 μs Fig. 11. Body diode forward characteristics; typical values



 T_{j} = 175 °C; t_{p} < 200 μs Fig. 12. Body diode forward characteristics;



V_{DS} = 10 V; I_{DS} = 12 mA Fig. 13. Threshold voltage as a function of junction temperature



I_{DS} = 40 A; I_{GS} = 0.1 mA; V_{DS} = 800 V; T_j = 25 °C Fig. 14. Gate-source voltage as a function of gate charge; typical values

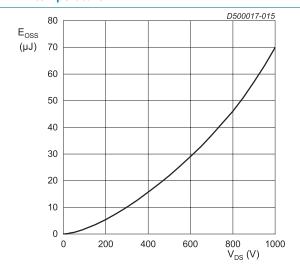
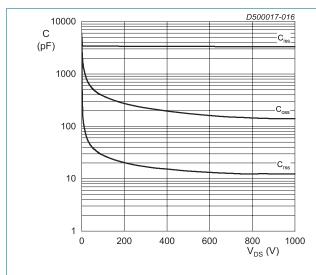
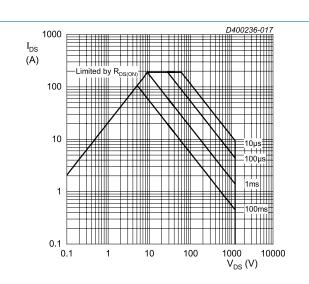


Fig. 15. Output capacitor stored energy as a function of drain-source voltage



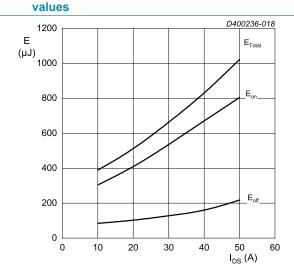
 $V_{DS} = 0 - 1000 V$

 $T_j = 25 \, ^{\circ}C; \, V_{AC} = 25 \, mV; \, f = 1 \, MHz$ Fig. 16. Input, output and reverse transfer capacitances as a function of drain-source voltage; typical



 $T_i = 25 \,^{\circ}C; D = 0$ Parameter: t₀

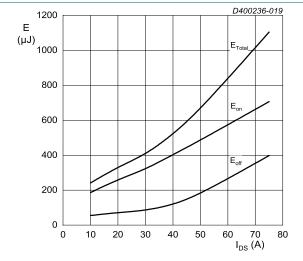
Fig. 17. Forward bias safe operating area



 T_{j} = 25 °C; V_{DD} = 800 V; $R_{G(ext)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

FWD = WNSC2M30120TB-A

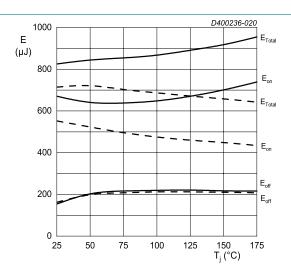
Fig. 18. Clamped Inductive Switching Energy as a function of drain current



 T_{j} = 25 °C; V_{DD} = 600 V; $R_{G(ext)}$ = 5.1 $\Omega;$ V_{GS} = -4 V/18 V; L = 100 μH

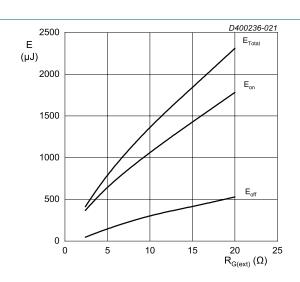
FWD = WNSC2M30120TB-A

Fig. 19. Clamped Inductive Switching Energy as a function of drain current



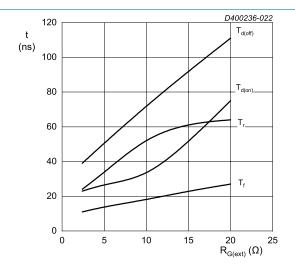
$$\begin{split} I_{DS} &= 40 \text{ A; V}_{DD} = 800 \text{ V; R}_{G(ext)} = 5.1 \text{ }\Omega; \\ V_{GS} &= -4 \text{ V}/18 \text{ V; L} = 100 \text{ }\mu\text{H} \\ FWD &= WNSC2M30120TB-A \end{split}$$

Fig. 20. Clamped Inductive Switching Energy as a function of junction temperature



 $T_{\rm j}$ = 25 °C; $V_{\rm DD}$ = 800 V; $I_{\rm DS}$ = 40 A; $V_{\rm GS}$ = -4 V/18 V FWD = WNSC2M30120TB-A; L = 100 μH

Fig. 21. Clamped Inductive Switching Energy as a function of external gate resistance



 $T_j = 25~^{\circ}C;~V_{DD} = 800~V;~I_{DS} = 40~A;~V_{GS} = -4~V/18~V$ FWD = WNSC2M30120TB-A; L = 100 μ H Fig. 22. Switching time as a function of external gate

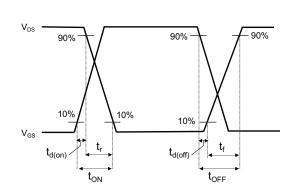
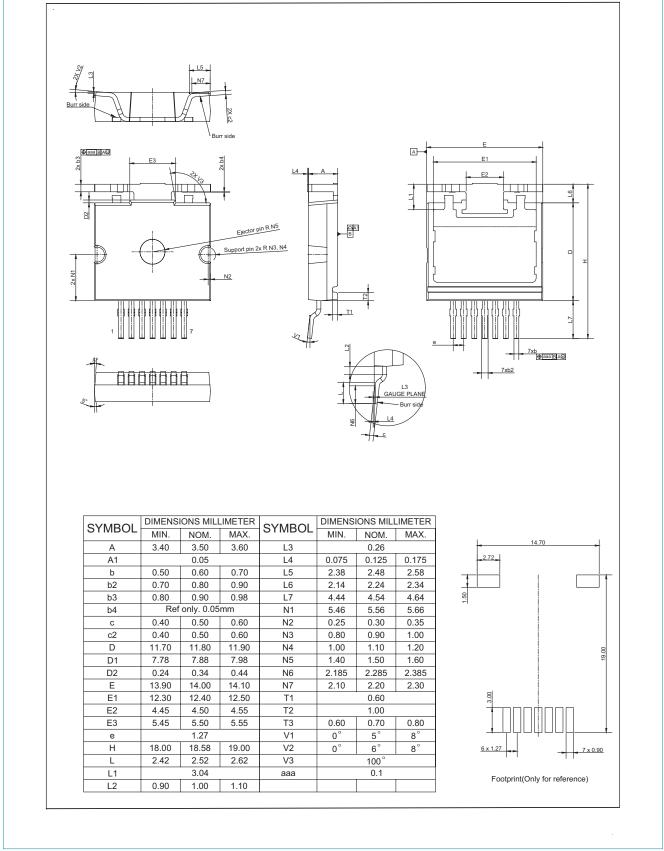


Fig. 23. Switching time definition

resistance

11. Package outline



12. Legal information

Data sheet status

Document status [1][2]	Product status [3]	Definition
Objective [short] data sheet	Development	This document contains data from the objective specification for product development.
Preliminary [short] data sheet	Qualification	This document contains data from the preliminary specification.
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